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Sheet	1	Of	8

COMPLETE IF KNOWN				
Application Number	10/026, 020			
Filing Date	December 27, 2001			
First Named Inventor	Ralph Johnson			
Art Unit	2828			
Examiner Name	Tuan M Nguyen			
Attorney Docket Number	V637-02670 US			

-:			***	U.S. PATE	NT DOCUMENTS	
Examiner Initials*	Cite No ¹	Document Number	lumber Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
TN	 	US 4445218	<u> </u>	04-24-1984	Coldren	
TN.		US 4608697		08-26-1986	Coldren	
TN		US 4622672		11-11-1986	Coldren et al.	/
TN	<u> </u>	US 4829347		05-09-1989	Cheng et al.	
·7N	<u> </u>	US 4873696		10-10-1989	Coldren et al.	
TN	 	US 4896325		01-23-1990	Coldren	
TN		US 5045499		09-03-1991	Nishizawa et al.	
TN	 	US 5082799	A	01-21-1992	Holmstrom et al.	
TN	 	US 5245622	Α	09-14-1993	Jewell et al.	
TN	<u> </u>	US 5251225	A	10-05-1993	Eglash et al.	
TN	<u> </u>	US 5293392	A	03-08-1994	Shieh et al.	/
TN		US 5343487	Α	08-30-1994	Scott et al.	
TN		US 5358880	Α	10-25-1994	Lebby et al.	
TN	<u> </u>	US 5365540	A	11-15-1994	Yamanaka	
TN	 	US 5392307	A	02-21-1995	Sugiyama et al.	
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TN		US 5468343	Α	11-21-1995	Kitano	
TN		US 5491710	Α	02-13-1996	Lo	
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TN	<u> </u>	US 5631472	Α	05-20-1997	Cunningham et al.	
TN	1	US 5693180	Α	12-02-1997	Furukawa et al.	
TN		US 5719891	Α	02-17-1998	Jewell	/
TN		US 5719894	Α	02-17-1998	Jewell et al.	Y

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet	2	Of	8

COMPLETE IF KNOWN					
Application Number	10/026, 020				
Filing Date	December 27, 2001				
First Named Inventor	Ralph Johnson				
Group Art Unit	2828				
Examiner Name	Tuan M Nguyen				
Attorney Docket Number	V637-02670 US				

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TN	US 5719895	Α .	02-17-1998	Jewell et al.	Δ
TN	US 5729567	Α	03-17-1998	Nakagawa	
TN.	US 5732103	Α	03-24-1998	Ramdani et al.	
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TN	US 5754578	A	05-19-1998	Jayaraman	
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TV	US 6046065	Α	04-04-2000	Goldstein et al.	
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TN	US 6061381	Α	05-09-2000	Adams et al.	1

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COMPLETE IF KNOWN				
Application Number	10/026, 020			
Filing Dat	December 27, 2001			
First Named Inventor	Ralph Johnson			
Group Art Unit	2828			
Examiner Name	Tuan M Nguyen			
Attorney Docket Number	V637-02670 US			

71	US 6121068	A	09-19-2000	Ramdani et al.
TN	US 6127200	Α	10-03-2000	Ohiso et al.
71/	US 6148016	A	11-14-2000	Hegblom et al.
TN	US 6195485	B1	02-27-2001	Coldren et al.
TN.	US 6207973	B1	03-27-2001	Sato et al.
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TW	US 6362069	B1	03-26-2002	Forrest et al.
TN	US 6366597	B1	04-02-2002	Yuen et al.
TN.	US 6372533	B2	04-16-2002	Jayaraman et al.
TN	US 6424669	B1	07-23-2002	Jiang et al.
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TN	US 6542530	B1	04-01-2003	Shieh et al.
th	US 2002/ 0067748	A1	06-06-2002	Coldren et al.
w	US 2002/ 0071464	A1	06-13-2002	Coldren et al.
TN	US 2002/ 0075920	· A1	06-20-2002	Spruytte et al.
TN	US 2002/ 0071471	A1	06-13-2002	Kim et al.
W	US 2002/ 0075929	A1	06-20-2002	Cunningham
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TN	US 2002/ 0131462	A1	09-19-2002	Line et al.
TN	US 2003/ 0053510	A1	03-20-2003	Yuen et al.

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СОМЕ	PLETE IF KNOWN
Application Number	10/026, 020
Filing Date	December 27, 2001
First Named Inventor	Ralph Johnson
Group Art Unit	2828
Examiner Name	Tuan M Nguyen
Attorney Docket Number	V637-02670 US

				FOF	REIGN PATEN	T DOCUMENTS		
Examiner Initials*	Cite No ¹	Fo Country Code ³	reign Patent Doo	cument Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ⁶
TN		EP	0 740 377	A1	10-30-1996	Hewlett-Packard Company		17
TN		EP	0 740 377	В	10-30-1996	Hewlett-Packard Company		1
TN		EP	0 765 014	· A1	03-26-1997	France Telecom		I
TN		EP	0 765 014	B1	07-28-1999	France Telecom	1	
TN		EP	0 822 630	A1	02-04-1998	Hewlett-Packard Company		
TN		EP	0 874 428	A2	10-28-1998	Motorola, Inc.		
TN		EP	0 874 428	A3	11-04-1998	Motorola, Inc.		
TN		EP	0 874 428	B1	15-04-1998	Motorola, Inc.	1	
TN,		EP	1 294 063	A1	03-19-2003	Avalong Photonics AG		
TN		JP	57026492	A	02-12-1982	NEC Corp.		1.
TN		wo	98/007218	A1	02-19-1998	W.L. Gore & Associates, Inc.		
TN		wo	00/033433	A2	06-08-2000	Arizona Board of Regents		
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TN		wo	00/038287	A1	06-29-2000	Honeywell, Inc.		
TN		wo	00/052789	A2	02-29-2000	The Regents of the University of California		
TN		wo	00/052789	A3	02-29-2000	The Regents of the University of California		
TN		wo	00/065700	A2	11-02-2000	Gore Enterprise Holdings, Inc.		
TN		wo	00/065700	A3	11-02-2000	Gore Enterprise Holdings, Inc.		
TN		wo	01/016642	A2	03-08-2001	Agility Communications		
TN		wo	01/016642	A3	03-08-2001	Agility Communications	T /	
TN		wo	01/017076	A2	03-08-2001	The Regents of the University of California		
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Sheet	5	Of	8

COMF	PLETE IF KNOWN			
Application Number	10/026, 020			
Filing Date	December 27, 2001			
First Named Inventor	Ralph Johnson			
Group Art Unit	2828			
Examiner Name	Tuan M Nguyen			
Attorney Docket Number	V637-02670 US			

TN		wo	01/018919	A1	03-15-2001	The Regents of the University of California	/
TN		wo	01/024328	A2	04-05-2001	Agility Communications	
EN		wo	01/024328	A3	04-05-2001	Agility Communications	
TN		wo	01/033677	A2	05-10-2001	Arizona Board of Regents	
TW	7	wo	01/033677	A3	05-10-2001	Arizona Board of Regents	
TN		wo	01/084682	A2	11-08-2001	Agility Communications, Inc.	
TN		wo	01/093387	A2	12-06-2001	Sandia Corporation	
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TN		wo	01/095444	A2	12-13-2001	Agility Communications, Inc.	
TN		wo	01/098756	A2	12-27-2001	The Regents of the University of California	
TN		wo	02/003515	A2	01-10-2002	Agility Communications, Inc.	
TN		wo	02/017445	A1	02-28-2002	The Regents of the University of California	
TN		wo	02/084829	A1	10-24-2002	Cielo Communications, Inc.	/

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T²
TN		ALMUNEAU, G., et al., "Accurate control of Sb composition in AlGaAsSb alloys on InP substrates by molecular beam epitaxy", article, Journal of Crystal Growth, Vol 208, 05-06-1999, pgs 113-6.	
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Examiner Signature Date Considered S-6	 · · · · · · · · · · · · · · · · · · ·		
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Application Number	10/026, 020
Filing Date	December 27, 2001
First Named Inventor	Ralph Johnson
Group Art Unit	2828
Examiner Name	Tuan M Nguyen
Attorney Docket Number	V637-02670 US

CAMPBELL, J., et al., "Quantum dot resonant cavity photodiode with operation near 1.3 µm wavelength", article, Electronics Letters, Vol 33, No 15, 07-17-1997,pgs 1337-9.
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet	7	Of	. 8

COMPLETE IF KNOWN		
Application Number	10/026, 020	
Filing Date	December 27, 2001	
First Named Inventor	Ralph Johnson	
Group Art Unit	2828	
Examiner Name	Tuan M Nguyen	
Attorney Docket Number	V637-02670 US	

TU	KIM, J., et al., "Epitaxially-stacked multiple-active-region 1.55 μm lasers for increased differential efficiency", article, Applied Physics Letters, Vol 74, No 22, 05-31-1999, pgs 3251-3.
TN	KIM, J., et al., "Room-temperature, electrically-pumped multiple-active-region VCSELs with high differential efficiency at 1.55 μm", article, Electronics Letters, Vol 35, No 13, 06-24-1999, pgs 1-2.
TN	KOTAKI, Y., et al., "GalnAsP/InP surface emitting layser with two active layers", article, Extended Abstracts of the 16 th (1984 International) conference on Solid State Devices and Materials, pgs 133-6.
TOV	KOYAMA, F., et al., "Room temperature CWS operation of GaAs vertical cavity surface emitting laser", article, The Transactions of the IEICE, Vol E71, No 11, Nov 1988, pgs 1089-90.
W	LARSON, J., et al., "GalnNAs-GaAs long-wavelength vertical-cavity surface-emitting laser diodes", article, IEEE Photonics Technology Letters, Vol 10, No 2, Feb 1998, pgs 188-90.
FN	LEE, Y., et al., "Physics and nonlinear device applications of bulk and multiple quantum well GaAs", invited paper, SPIE Vol 792 Quantum Well and Superlattice Physics (1987), pgs 128-133.
TN	LI, J., et al., "Persistent photoconductivity in Ga _{1-x} In _x N _y As _{1-y} ", article, Applied Physics Letters, Vol 75, No 13, 09-27-1999, pgs 1899-1901.
TN	MIRIN, R., et al., "1.3 μm photoluminescence from InGaAs quantum dots on GaAs", article, Applied Physics Letter 67 (25), 12-18-1995, pgs 3795-7.
TN	NAKAGAWA, S., et al., "1.55 μm InP-lattice-matched VCSELs with AlGaAsSb-AlAsSb DBRs", article, IEEE Journal on Selected Topics in Quantum Electronics, Vol 7, No 2, Mar/Apr 2001, pgs 224-30.
TN	NAKAHARA, K., et al., "1.3 μm continuous-wave lasing operation in GalnNAs quantum-well lasers", article, IEEE Photonics Technology Letters, Vol 10, No 4, Apr 1998, pgs 487-8.
TN	NAONE, R., et al., "Tapered air apertures for thermally robust VCL structures", article, IEEE Photonics Technology Letters, Vol 11, No 11, Nov 1999, pgs 1339-41.
TN	NELSON, D., et al., "Band nonparabolicity effects in semiconductor quantum wells", article, Rapid Communications, Vol 35, No 17, 02-15-1987, pgs 7770-7773.
TN	OHNOKI, N., et al., "Superlattice AIAs/AllnAs-oxide current aperture for long wavelength InP-based vertical-cavity surface-emitting laser structure", article, Applied Physics Letters, Vol 73, No 22, 11-30-1998, pgs 3262-4.
TN	ORTSIEFER, M., et al., "Submiliamp long-wavelength InP-based vertical-cavity surface-emitting laser with stable linear polarization", article, Electronics Letters, Vol 36, No 13, 06-22-2000, pgs 1124-6.
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TN	PETERS, M., et al., "Band-gap engineered digital alloy interfaces for lower resistance vertical-cavity surface-emitting lasers, article, Applied Physics Letters, Vol 63, No. 25, Dec 1993, pgs 3411-3.
TN	PIPREK, J., et al., "Thermal comparison of long-wavelength vertical-cavity surface-emitting laser diodes", Electronics Letters, 05-26-1994, Vol 30, No 11, pgs 866-868.
TN	PIPREK, J., et al., "Minimum temperature sensitivity of 1.55 µm vertical-cavity lasers at -30 nm gain offset", article, Applied Physics Letters, Vol 72, No 15, 04-13-1998, pgs 1814-6.
TW	RAJA, M., et al., "Novel wavelength-resonant optoelectronic structure and its application to surface-emitting semiconductor lasers", article, Electronics Letters, 09-01-1988, Vol 24, No 18, pgs 1140-1142.
TN	SCOTT, J., et al., "High efficiency submilliamp vertical cavity lasers with intracavity contacts", article, IEEE Photonics Technology Letters, Vol 6, No 6, Jun 1994, pgs 678-80.

Examiner Signature Many Manyon	Date Considered	5-20-03
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Attorney Docket Number	V637-02670 US		

TN	SEKIGUCHI, S., et al., "Long wavelength GalnAsP/InP laser with n-n contacts using AlAs/InP hole injecting tunnel junction", article, Japanese Journal of Applied Physics, Part 2, No 4B, 04-15-1999, pgs L443-5.	
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TN	SUGIMOTO, M., et al., "Surface emitting devices with distribut4ed Bragg reflectors grown by highly precise molecular beam epitaxy", article, Journal of Crystal Growth, Vol 127, 1993, pgs 1-4.	
TN	UCHIDA, T., et al., "CBE grown 1.5 μm GalnAsP-InP surface emitting lasers", article, IEEE Journal of Quantum Electronics, Vol 29, No 6, Jun 1993, pgs 1975-80.	
TN	VAN DE WALLE, C. "Band lineups and deformation potentials in the model-solid theory", article, Physical Review B, Vol 39, No 3, 01-15-1989, pgs 1871-83.	
TN	WHITAKER, T., "Long wavelengths VCSELs move closer to reality", article, Compound Semiconductor, July 2000, pgs 65-7.	•
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UN.	YAMADA, M., et al., "Room temperature low-threshold CW operation of 1.23 µm GaAsSb VCSELs on GaAs substrates", article, Electronics Letters, 03-30-2000, Vol 36, No 7, pgs 637-638.	
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m.	YANG, X., et al., "InGaAsNSb/GaAs quantum wells for 1.55 μm lasers grown by molecular-beam epitaxy", article, Applied Physics Letters, Vol 78, No 26, pgs 4068-70.	
n	YANO, M., et al., "Time-resolved reflection high energy electron diffraction analysis for atomic layer depositions of GaSb by molecular beam epitaxy", article, Journal of Crystal Growth, Vol 146, 1995, pgs 349-53.	
in	YUEN, W., et al., "High-performance 1.6 µm single-epitaxy top-emitting VCSEL", article, Electronics Letters, Vol 36, No 13, 06-22-2000, pgs 1121-3.	

Examiner Signature	Than	Nacyen		Date Considered	5-20-03
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